

**Search Notes****Application/Control No.**

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**Examiner**

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**Applicant(s)/Patent under Reexamination**

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**Art Unit**

2611

**SEARCHED**

Class	Subclass	Date	Examiner
375	229	8/16/2007	EB
375	232	8/16/2007	EB
375	233	8/16/2007	EB
375	234	8/16/2007	EB

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	8/16/2007	EB

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner